

2023 IEEE European Test Symposium (ETS 2023)

**Venezia, Italy
22-26 May 2023**



**IEEE Catalog Number: CFP23216-POD
ISBN: 979-8-3503-3635-1**

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IEEE Catalog Number:	CFP23216-POD
ISBN (Print-On-Demand):	979-8-3503-3635-1
ISBN (Online):	979-8-3503-3634-4
ISSN:	1530-1877

Additional Copies of This Publication Are Available From:

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